

## Overlength Page Charge Agreement – Terms & Conditions

### IEEE Instrumentation and Measurement Society Journals (TIM and OJIM)

Overlength pages are charged to both discourage verbose papers and recover expenses for papers that are too long, because IEEE charges the Instrumentation and Measurement Society (IMS) per page for editing, composition, administration, and other processing costs. As such, using IEEE's standard double-column transactions template as the baseline, the free page limit for IMS journals/transactions is as follows:

Regular Papers:	eight (8) pages
Survey/Review Papers:	eighteen (18) pages
Short Papers:	three (3) pages
Special Section Papers:	eight (8) pages, unless stated otherwise by the Special Section

For each page or fraction thereof beyond the above-mentioned free page limit, there is a mandatory overlength page charge of \$265 for non-IMS members or \$220 for IMS members\*, plus applicable taxes. Membership is checked at the time of invoicing.

Accepted papers that go above the free page limit, will be invoiced by the IEEE or its subcontractor during the publication process of the paper. The exact number of pages of an accepted paper will be determined after IEEE's editing process, and not before. Except for the discounts specified below, overlength charges will not be waived under any circumstances.

**Discounts:** Corresponding authors from low-income countries, as defined by [The World Bank classification of economies](#), are eligible for a 100% waiver, while corresponding authors from lower- middle-income countries are eligible for a discount ranging from 25% to 50% based on the GDP of the country of the corresponding author.

**Accepting the Terms & Conditions of this Overlength Page Charge Agreement during the submission process in PeerTrack obligates ONE author who is in the position of financial authority who can commit him/her or his/her institution. That author must be identified at the time of manuscript submission in PeerTrack.**

---

\* At least one author must be a graduate student or full IMS member.